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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10084987	02/28/2002	356	356	2877	1-0111/05

**\*\*APPLICANTS:** Stirton James; Lensing Kevin; Nariman Hormuzdiar; Reeves Steven;

**\*\*CONTINUING DATA VERIFIED:**

**\*\* FOREIGN APPLICATIONS VERIFIED:**

PG-PUB DO NOT PUBLISH ☒

RESCIND ☐

Foreign priority claimed ☐ yes ☐ no  
35 USC 119 conditions met ☐ yes ☐ no  
Verified and Acknowledged Examiners's initials

ATTORNEY DOCKET NO

2000.092400

**TITLE :** Method of using high yielding spectra scatterometry measurements to control semiconductor manufacturing processes, and systems for accomplishing same

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	Total Claims
			Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sketches Drawn	Fig. Drawn
		Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner	Application Examiner
		PREPARED FOR ISSUE	
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